

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	670	382/151.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/17 09:43
L2	1323	382/149,151.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/17 09:43
L3	1529	382/147,149,151.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/17 09:44
L4	2237	382/145,147,149,151.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/17 09:44
L5	2585	382/144,145,147,149,151.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/17 09:44
L6	254	382/144,145,147,149,151.ccls. and (overlay)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/17 09:44
L7	38	382/144,145,147,149,151.ccls. and (overlay)with correct\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/17 09:57

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L8	2465	(overlay)with correct\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/17 09:57
L9	283	(overlay)with correct\$4 and process with variation	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/17 09:58
L10	83	(overlay)with correct\$4 and process with variation and grid	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/17 09:58
L11	118	(overlay)with correct\$4 and process with variation and grating	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/17 09:59
L12	71	(overlay)with correct\$4 and process near5 variation and grating	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/17 09:59
L13	39	(overlay)with correct\$4 and process near5 variation with overlay and grating	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/17 09:59
L14	0	("6949462,6958819").PN.	USPAT; EPO	OR	OFF	2007/12/17 11:35
L15	0	("6949462or6958819").PN.	USPAT; EPO	OR	OFF	2007/12/17 11:35
L16	1	("6949462").PN.	USPAT; EPO	OR	OFF	2007/12/17 11:36
L17	1	("6958819").PN.	USPAT; EPO	OR	OFF	2007/12/17 11:36

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L18	1	("6970225").PN.	USPAT; EPO	OR	OFF	2007/12/17 11:37
L19	1	("6970255").PN.	USPAT; EPO	OR	OFF	2007/12/17 11:37
L20	1	("6982793").PN.	USPAT; EPO	OR	OFF	2007/12/17 11:39
L21	1	("6992764").PN.	USPAT; EPO	OR	OFF	2007/12/17 11:40
L22	1	("7046361").PN.	USPAT; EPO	OR	OFF	2007/12/17 11:40
L23	1	("7061615").PN.	USPAT; EPO	OR	OFF	2007/12/17 11:40


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Weidong Yang; Lowe-Webb, R.; Heaton, J.; Dusa, M.; van der Schaaf, M.;
Advanced Semiconductor Manufacturing Conference and Workshop, 2003 IECON
31 March-1 April 2003 Page(s):46

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IEEE CNF IEEE Conference Proceeding

- 2. **Evaluation of the potential cartographic accuracy of Radarsat and JERS**
de Oliveira Andrade, N.S.; Alves, D.S.;
Geoscience and Remote Sensing Symposium, 2001. IGARSS '01. IEEE 2001
Volume 6, 9-13 July 2001 Page(s):2662 - 2664 vol.6
Digital Object Identifier 10.1109/IGARSS.2001.978122

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